

# **Activities for TRIZ Introduction and Penetration into Hitachi Group and Some Typical Application Cases**



---

**Setsuo Arita**

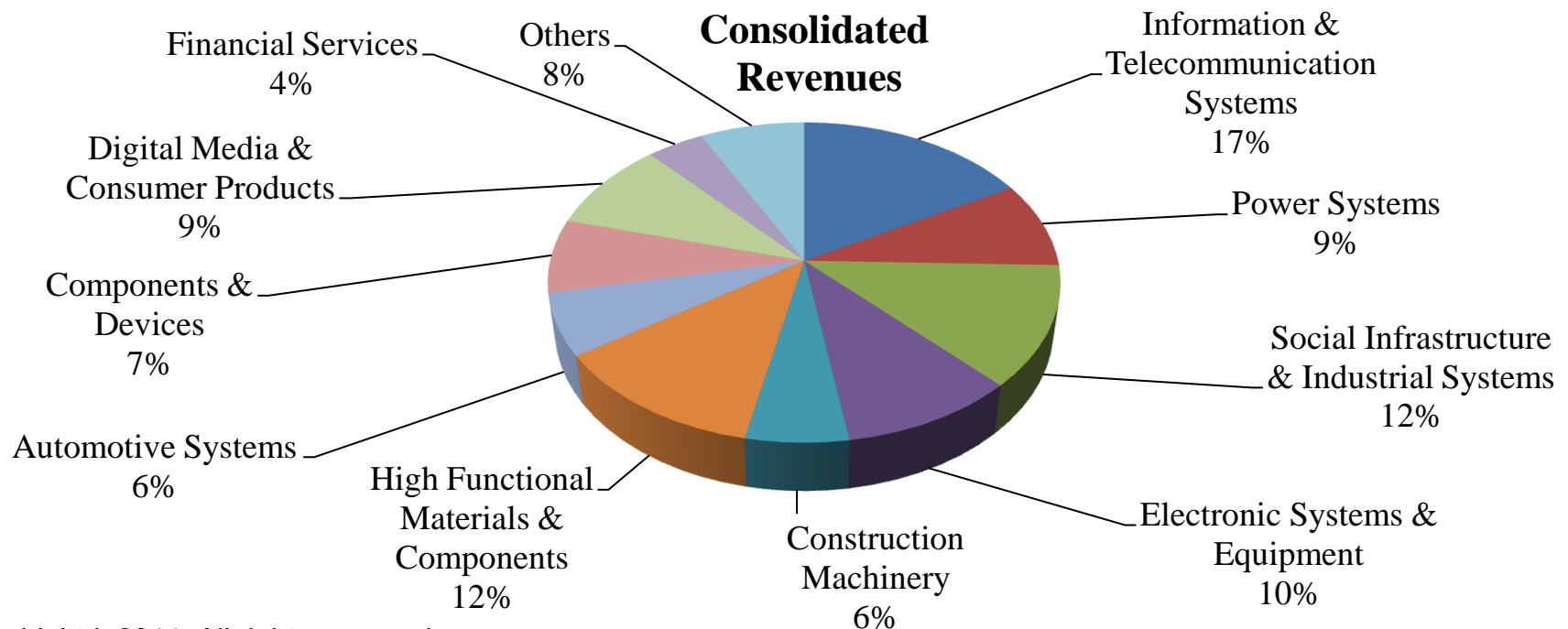
**Energy and Environmental Systems Laboratory**

**Hitachi, Ltd.**

# Overview of Hitachi Group

## Consolidated Basis (as of March 31, 2010)

|                |                             |
|----------------|-----------------------------|
| Corporate Name | Hitachi, Ltd                |
| Founded        | 1910 (Incorporated in 1920) |
| Revenues       | \8,968,546 million          |
| Employees      | 359,746                     |
| Subsidiaries   | 900                         |



# Motivation of Innovative Engineering of Hitachi Group

**In 1997, Hitachi, Ltd. decided to implement innovative engineering methods within all companies of the Hitachi Group to keep ahead of rapidly changing approaches in product development and design.**

- The Hitachi Group is a multinational corporation and its products are in various fields.
- The Hitachi Group is involved in a multitude of technical fields.
- Implementing a Group-wide improvement program seemed impossible.

# Strategy of Innovative Engineering

- Innovative engineering methods provide a strategy to understand and solve the essence of a problem by applying general solution techniques.
- Hitachi facilitated the introduction and penetration of these techniques.
- Hitachi promoted the development of more advanced methods based on them.
- **All engineers should acquire these techniques as general knowledge and basic skills.**



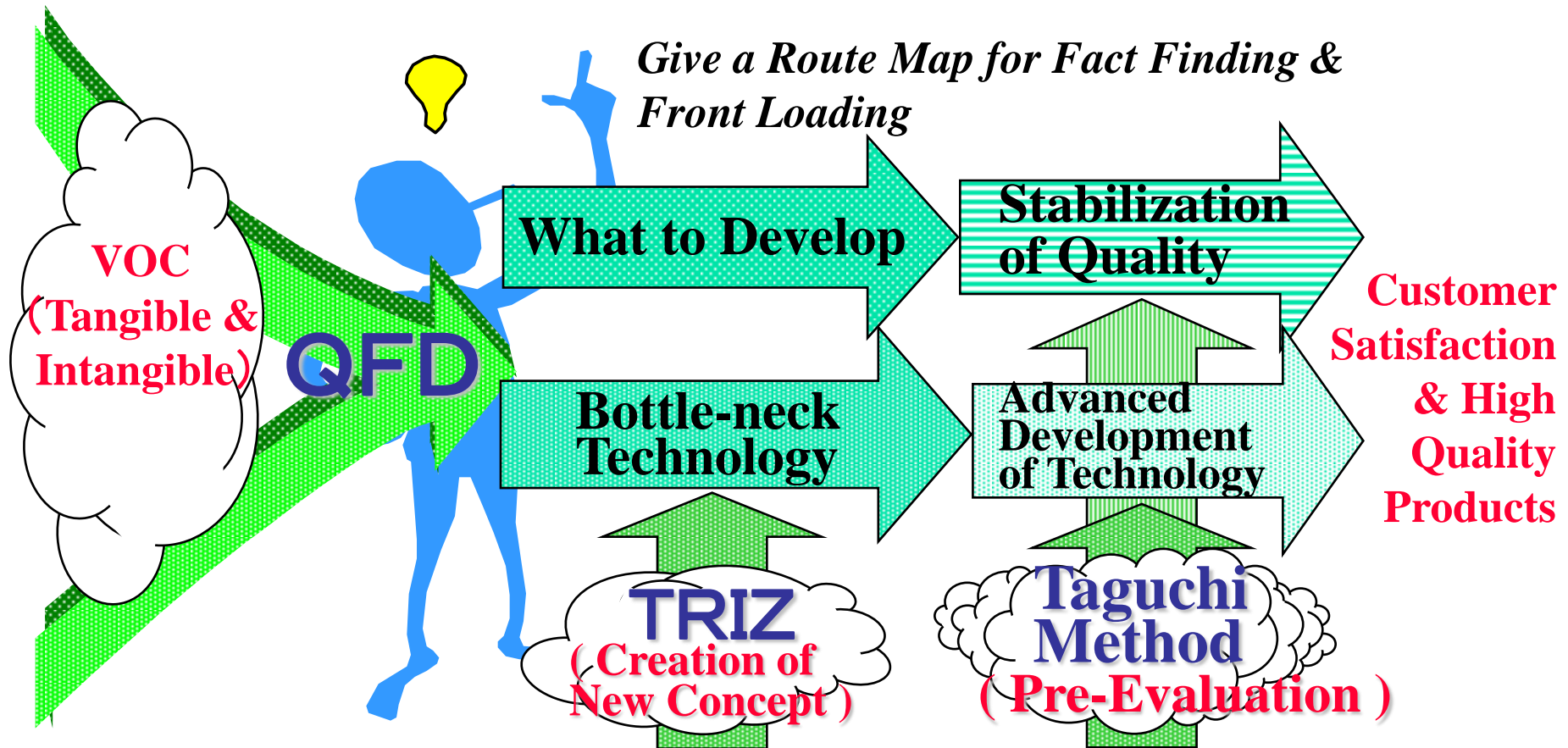
## **HiSPEED21**

“Hitachi Innovation Program toward Super Process with Excellent Engineering & Digital Technologies for the 21st Century”

# Contents of HiSPEED21

- QFD, TRIZ, and the Taguchi method were judged to play a major role in the product development and design processes.
- In 1999, the introduction and penetration of these techniques into the Hitachi Group was started.
- The use of various general problem solving techniques by engineers to enhance their engineering abilities was facilitated.
- Each division in the Hitachi Group was guided to promote the development of its leaders.

# Product Development and Design Processes



“Product Development and Design Process Engineering Technologies” Proposed by T. Hayashi\*

\*Former Senior Chief Engineer in Hitachi, Present Chairman of the Board of Japan TRIZ Society

# Introduction and Penetration Activities of TRIZ

- Educational materials including applications of the TRIZ were developed and used to help management leaders and engineers understand the essence of TRIZ.
- Leaders were taught how to apply TRIZ and then, how to teach engineers to apply TRIZ.
- The aim was an increase in adoption and penetration of TRIZ by holding forums on engineering techniques focused mainly on applications of TRIZ, and by holding regular meetings with the TRIZ leaders at the divisions.
- Regular follow-ups were held every six months.
- Hitachi commended engineers who obtained excellent results in TRIZ applications.



# Application Case of TRIZ to Actual Work as Educational Material

## Application Case

### Automatic Judgment of Intensity Degradation of Airport Lights

This application case appeared in *NIKKEI MECHANICAL* in September 2000.

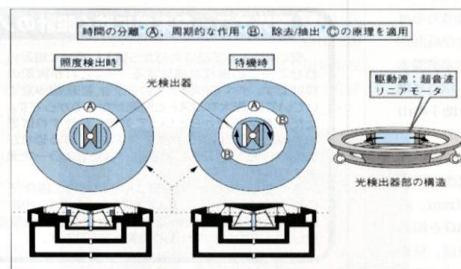
\*時間分離の原則 TRIZのテクニックの一つで、時間によって状態を変える方法  
 \*除去/抽出の原理 邪魔な部分、もしくは特性を取り除く  
 \*伸介の原理 伸介物を利用する  
 以下はTRIZの40の発明原理  
 \*周期的な作用の原理 周期的な動作に変える  
 \*アバウトの原理 100%の少し上または下を狙って、問題を大幅に簡素化  
 \*コピーの原理 そのものではなく、“コピー”を用いる  
 トピックス Topics テクノロジ Technology コスト・品質

### 日立、航空灯火の照度低下を検出する方法を創案 ハロゲンサイクルでフィラメントが細ると電気抵抗が増大

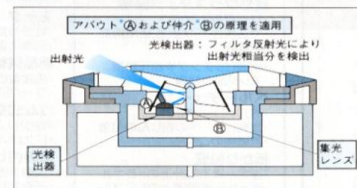
日立製作所の電力・電機グループにある電力・電機開発研究所(茨城県日立市)は、空港の滑走路に埋設した航空灯火の照度低下を検出する方法を、TRIZを使って複数考案した。特許を出願した。航空灯火の光源はハロゲンランプで、フィラメントのタングステンが蒸発すると、光源の電球内面にそれが蒸着して黒化する。その結果、照度が低下して航空機の操縦士からの視認性が悪くなるために電球を交換する必要がある。1日に1回程度は照度を測定しなければならない。従来は滑走路を人間が巡回して照度を検出、必要があればハロゲンランプを交換していた。新しく、オンラインで照度を検出する方法を考案する必要に迫られた。

そこで、TRIZを使って以下のような方法を考案した。途中のプロセスは省略して、結論だけ紹介する。

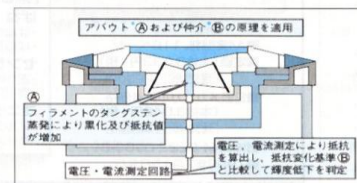
(1) 光源とガラス窓との間に、照度を検出するときだけ光検出器を置く回転式光検出法(図1)。この方式の欠点は、光検出器が照度を検出する間は、



【図1】光源とガラス窓との間に、照度を検出するときだけ光検出器を置く、回転式光検出法。光検出器が照度を検出する間は、光が通らない



【図2】フィルタは光を透過するだけでなく、光を反射する。反射した光量を測定する



【図3】フィラメントの径が細るということである。フィラメントが細ることにより電気抵抗値が増大することを利用する

光が通らないこと。そこでほかの方法も考えた。

(2) フィルタは光を透過するだけでなく、光を反射する。光源とフィルタとの間に光検出器を置いて、出射光の代わりにフィルタが反射した光量を測定する方法(図2)。光検出器を光源の近くに仕込まなければいけないのが難点と言え

ば、難点である。もっと理想的な方法はないだろうか。

(3) フィラメント、そしてハロゲンランプというランプの特性を最大限に活用すると光検出器がなくても、以下のようなことができる。光源の電球内面にフィラメントのタングステンが蒸着するという事は、フィラメントの径が細るということである。フィラメントが細ることにより電気抵抗値が増大することを利用する方法(図3)。フィラメントの電気抵抗値を照度の代替特性として測定する。フィラメントの電気抵抗値は、フィラメントそのもの電圧値と電流値を測定すれば、オームの法則から簡単に計算できる。

(篠原 司)



# Group-wide Committee for TRIZ Penetration into Hitachi Group

**Design and software technology committee**

**TRIZ penetration and development**

**Technology foresight-WG**

**-Chair: Prof. Kawabe  
-Aim: study and application**

**New generation TRIZ-WG**

**-Chair: Mr. Arita  
-Aim: use of Matrix-2003**

**Failure analysis -WG**

**-Chair: Mr. Arita  
-Aim: merge with KT-method**

**Inventive creativity strengthening-WG**

**-Chair: Mr. Ohsone  
-Aim: merge with conventional tools**

**Education curriculum preparation-WG**

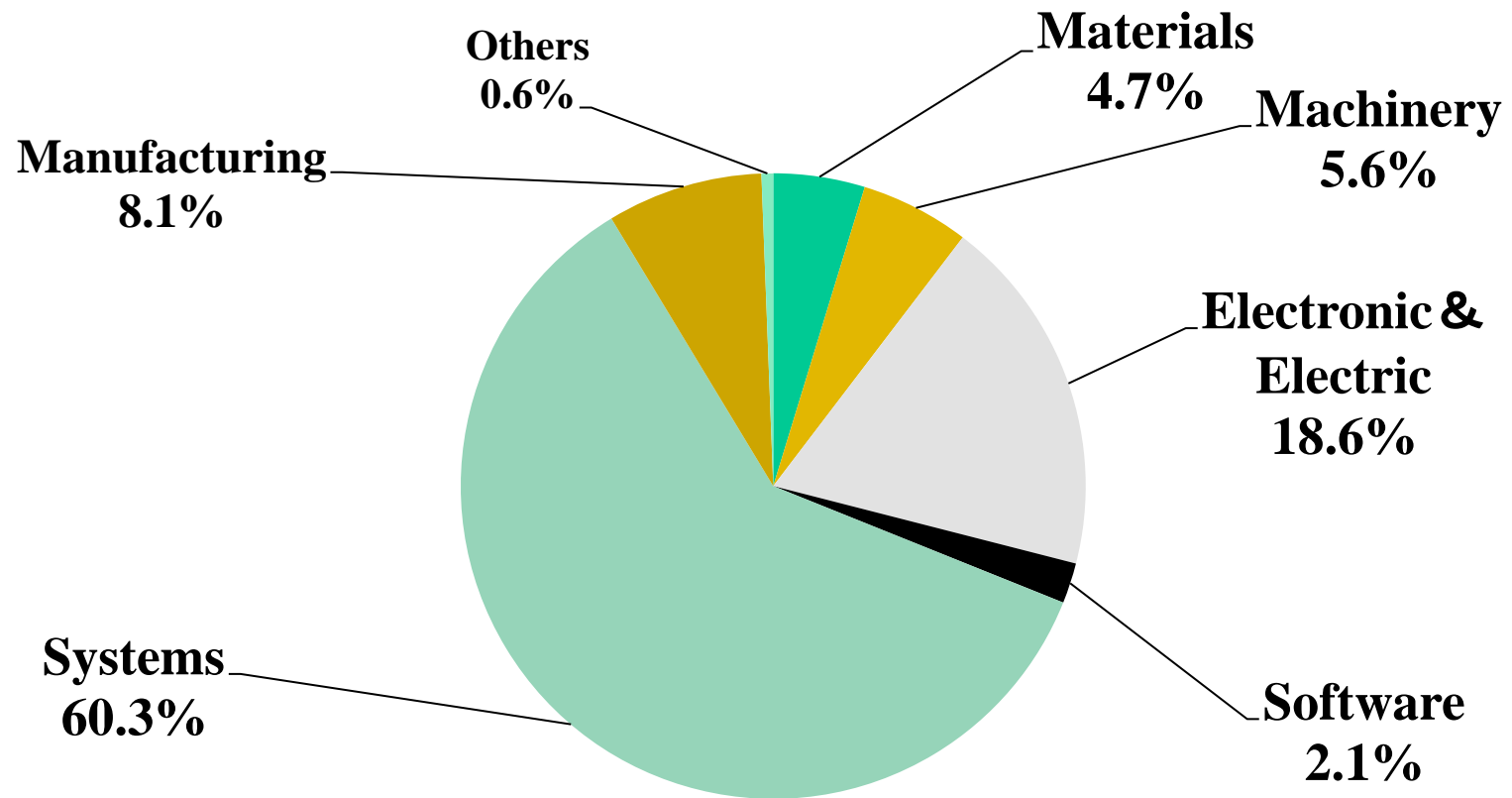
**-Chair: Mr. Nakahata  
-Aim: VOC-based curriculum**

**TRIZ-DE® -WG**

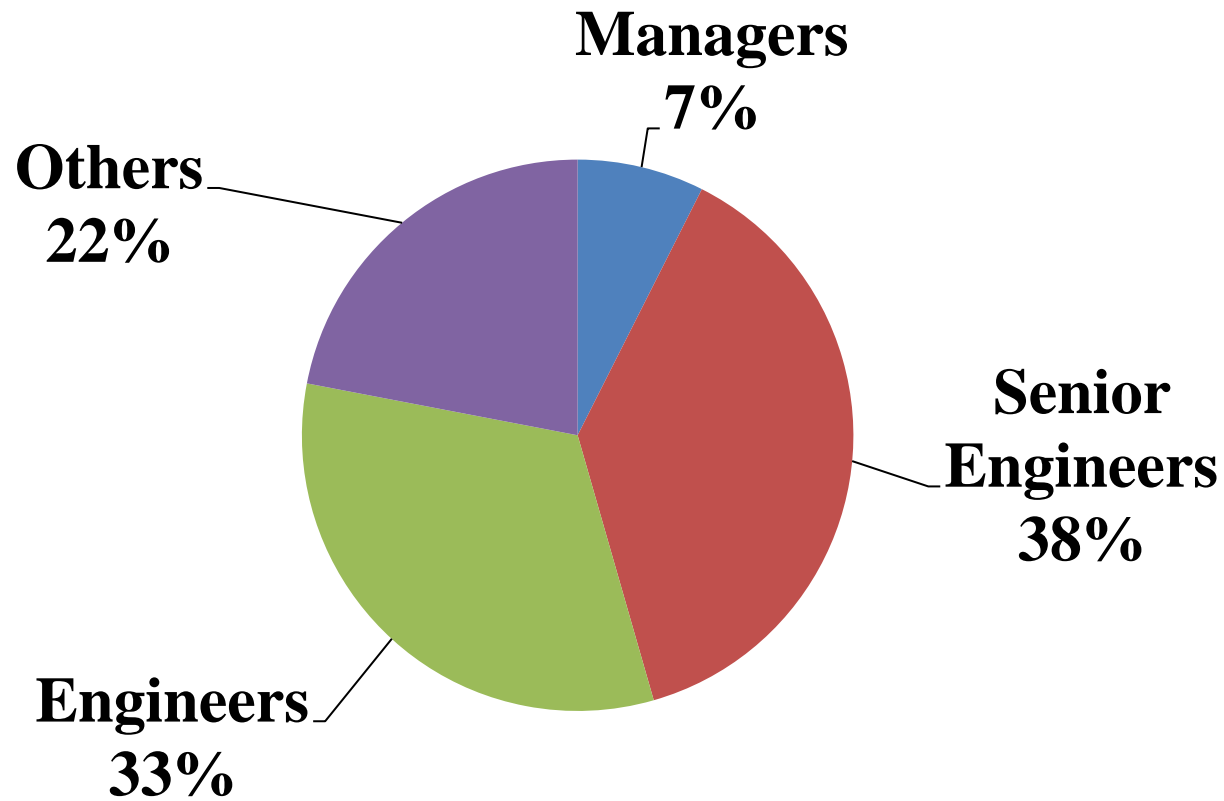
**-Chair: Mr. Nakamigawa  
-Aim: study and application**

# TRIZ Application Fields in Hitachi Group

■ Total number of TRIZ applications between 1997 and Sept. 2010 was about 3950.



# TRIZ Users by Position



# Energy and Environmental Systems Laboratory (EERL)





# R&D Fields of Power Systems at EERL

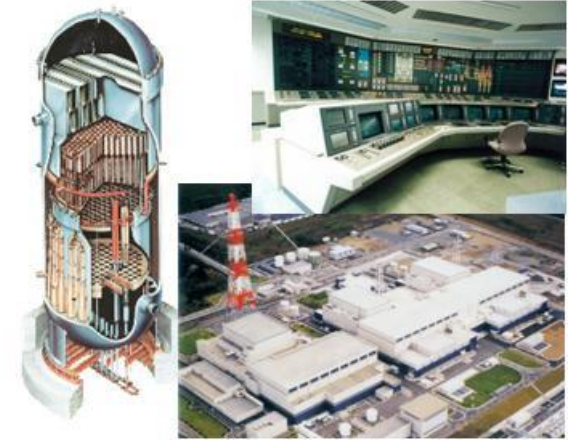
## Thermal Power



## Hydroelectric Power



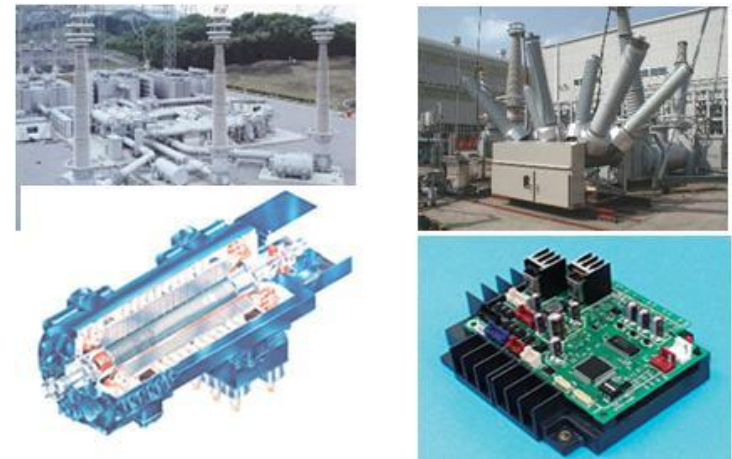
## Nuclear Systems



## Advanced Medical Systems



## Power & Industrial Systems



# R&D Fields of Industrial & Social Infrastructure Systems at EERL

## Transportation Systems



## Industrial & Social Infrastructure Systems

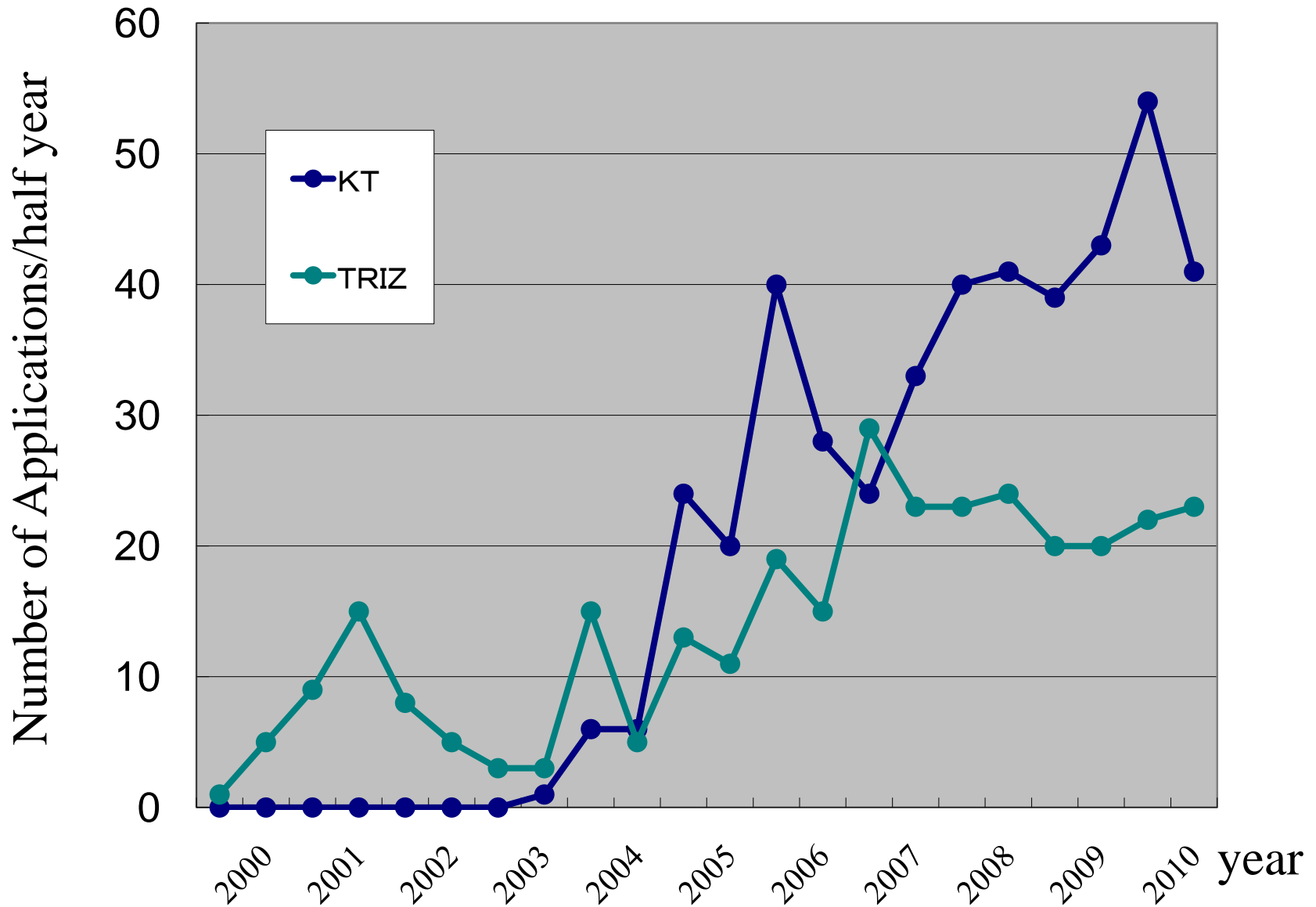


# Annual Schedule of Penetration Activities at EERL

- Promotion by top-down and bottom-up
- High evaluation score as an incentive

| Month       | 4             | 5   | 6            | 7            | 8 | 9            | 10            | 11                                  | 12              | 1                       | 2 | 3            |
|-------------|---------------|---|--------------|--------------|---|--------------|---------------|-------------------------------------|-----------------|-------------------------|---|--------------|
| Application |               | △<br>Committee Meeting  |              |              |   |              |               | △<br>Committee Meeting              | △<br>EERL Forum | △<br>Commendation Forum |   |              |
|             | ■<br>Planning |   | ■<br>Meeting | ■<br>Meeting |   | ■<br>Meeting | ■<br>Planning |                                     | ■<br>Meeting    | ■<br>Meeting            |   | ■<br>Meeting |
| Education   |               | △△△△<br>Newcomer Education<br>▪ KT-SPA<br>▪ QFD<br>▪ TRIZ<br>▪ Taguchi Method |              |              |   |              |               | △<br>Newcomer Education<br>▪ KT-SDM |                 |                         |   |              |

# Number of Applications at EERL





# Two Typical Application Cases

## Case 1

- Problem Solving for Insulation Breakdown of Enamel Wire

## Case 2

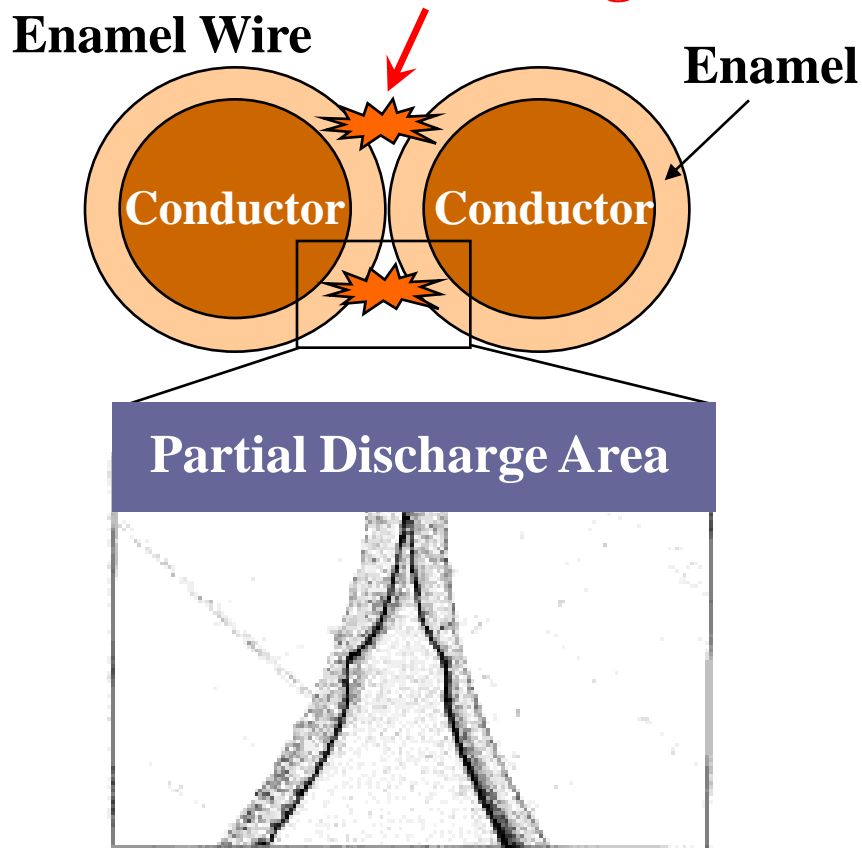
- Failure Analysis Merging TRIZ and Kepner-Tregoe® (KT)

# Case 1: Problem of Enamel Wire

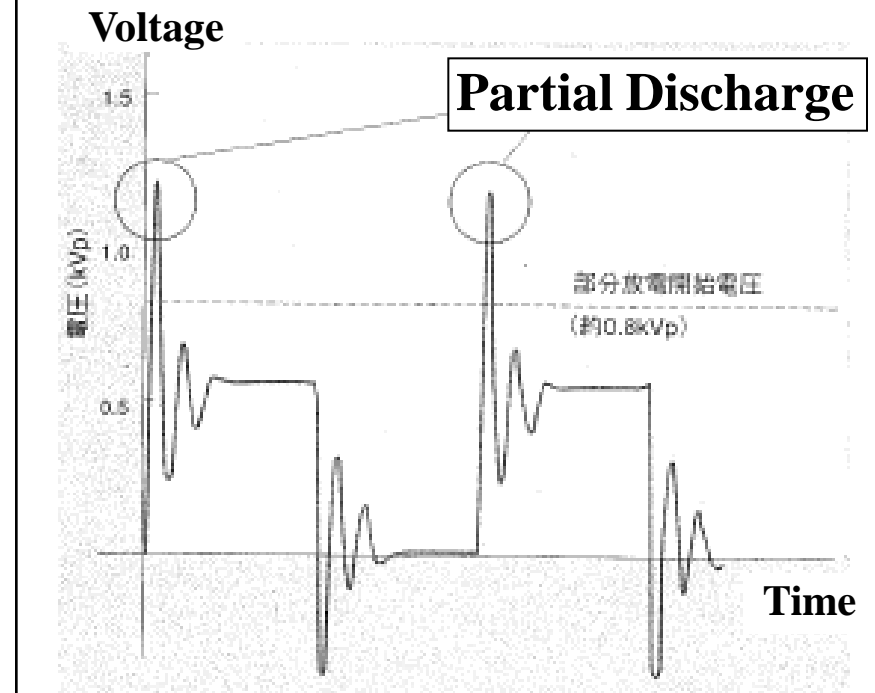
## Phenomena

- Many failures occurred in motors recently.
- Failures in the exchanged motors occurred again in a short time.

**Partial Discharge → Insulation Breakdown**



## Output Voltage of Inverter



# Application of Inventive Principle Based on Matrix 2003

## Improving Parameter

Improved immunity by blending in an inorganic insulation material

→ Improvement of reliability → Parameter 35 "Reliability/Robustness"

## Worsening Parameter

Worsened flexibility of wire

→ Parameter 34 "Ease of Operation"

## Inventive Principles

28 Mechanics Substitution

1 Segmentation

40 Composite Materials

29 Pneumatics & Hydraulics

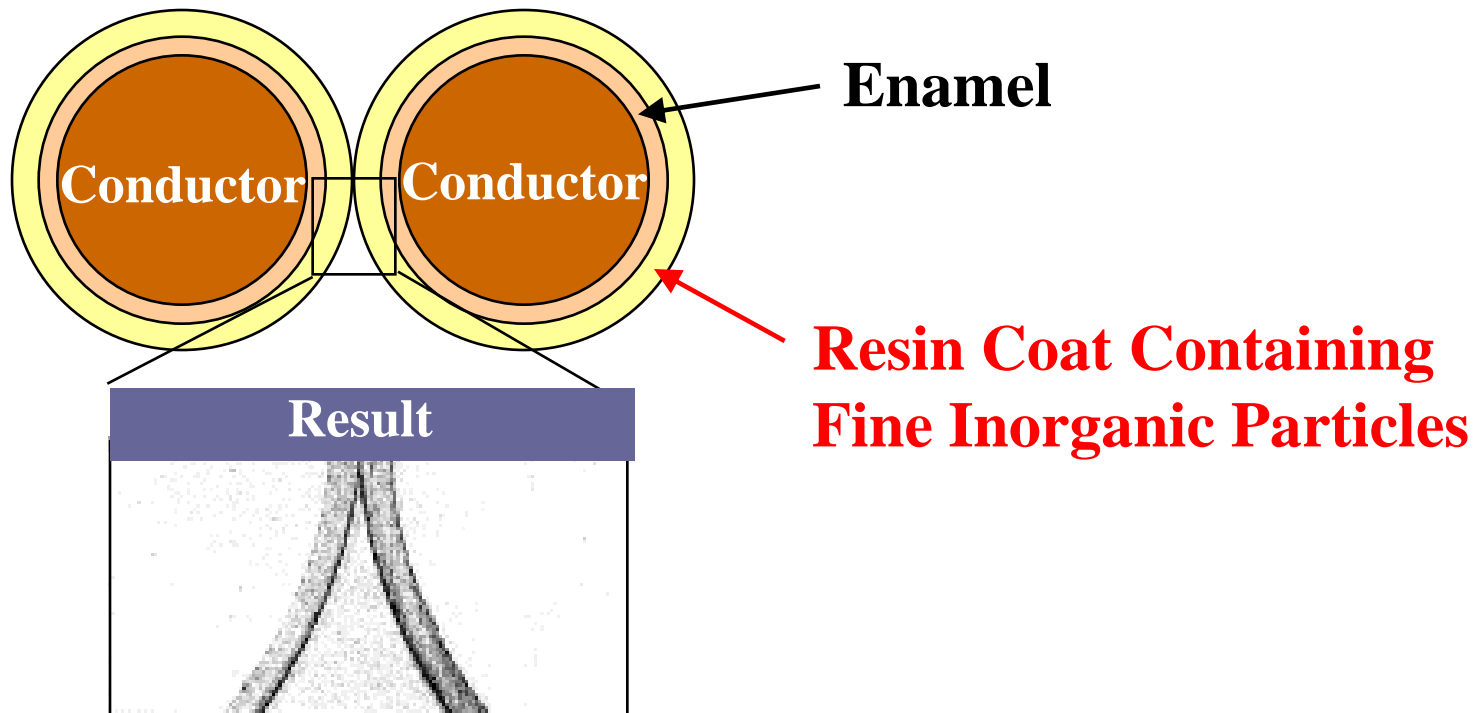


**Selection of Inventive Principal 1**

**→ Increase of Segmentation Ratio**

# Problem Solving for Enamel Wire

Increase of Segmentation Ratio → Fine Inorganic Particles  
Improvement of flexibility while maintaining immunity to surge



# Case 2: Failure Analysis Merging TRIZ and KT

## Background

- TRIZ-FA (Problem resolution based on subversion analysis)
    - Extraction of failure cause candidates by analyzing elements and functions
    - Difficulty in evaluation of probable causes
  - KT-PA
    - Evaluation of probable causes by describing four aspects of problem (What, Where, When, Extent)
    - Difficulty in establishment of probable causes
- [ KT-PA : Kepner Tregoe Problem Analysis ]

## Target

Proposal of an effective fault analysis method merging TRIZ-FA and KT-PA

# Outline of KT-PA

- (1) Description of the four aspects of problem (What, Where, When, Extent) about IS, ISNOT, Distinctions, and Changes
- (2) Establishment of probable causes by Distinctions and Changes, or knowledge and experiences
- (3) Evaluation of probable causes using IS/ISNOT pairs to find the Most Probable Cause (MPC)

IS: Observed event

IS NOT: Expected but unobserved event

Distinction: Feature of IS compared with IS NOT

Change:

- what is changed at Distinction
- what is changed around Distinction
- date/time of change

# Comparison of Failure Analysis by TRIZ-FA and KT-PA

| <b>Methods</b><br><b>Items</b> | <b>TRIZ-FA</b>   | <b>KT-PA</b>  |
|--------------------------------|--|---|
| <b>Merit</b>                   | <b>Rational cause extraction by functional diagram</b> | <b>Rational evaluation of probable cause by IS/IS NOT</b> |
| <b>Demerit</b>                 | <b>Difficulty in evaluation of probable causes</b>     | <b>Difficulty in establishment of probable causes</b>     |

# Failure Analysis Merging TRIZ-FA and KT-PA

## Cause Extraction Approach

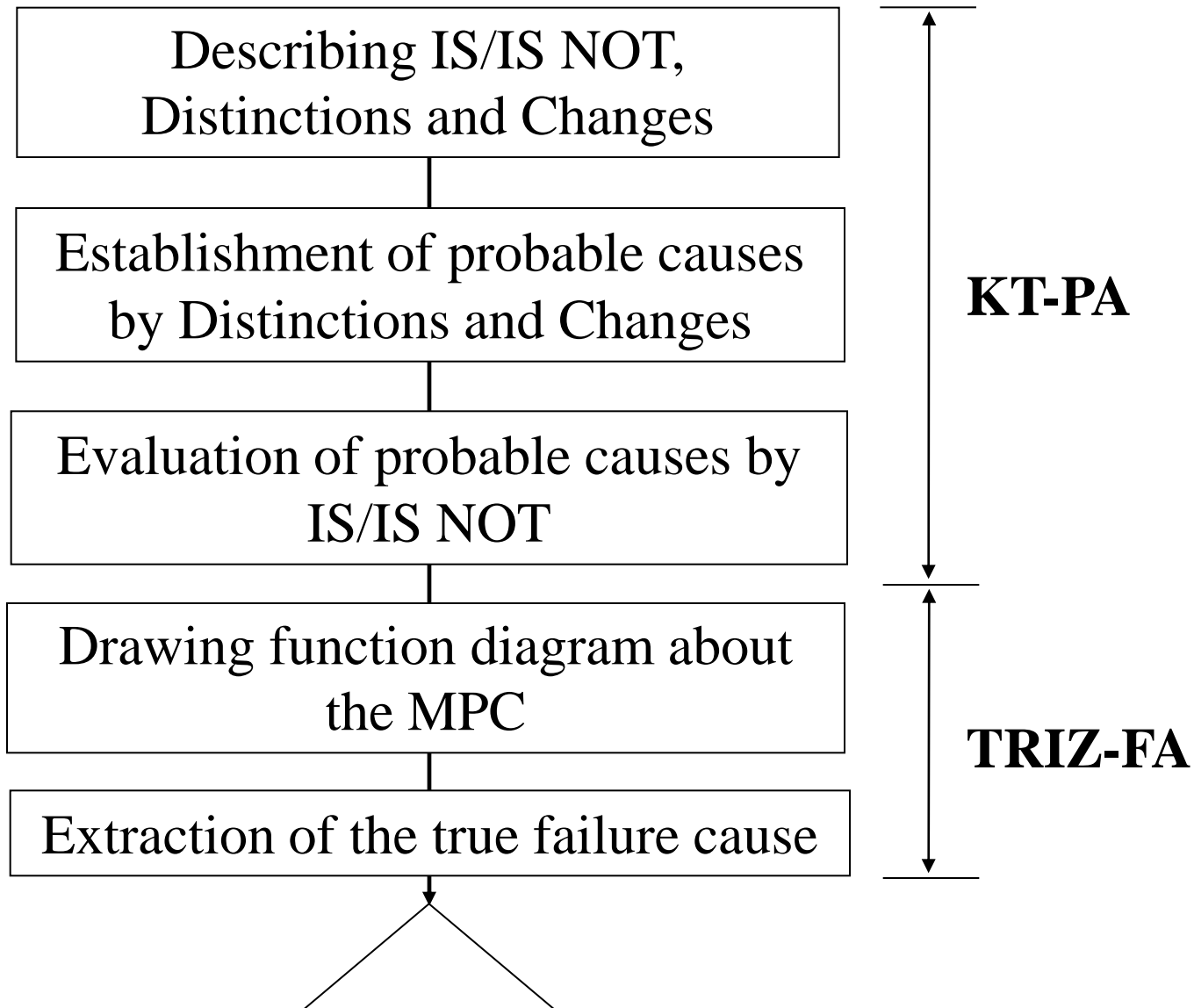
To extract the true failure cause by TRIZ-FA, after finding the most probable cause by KT-PA

## Cause Presumption Approach

To find the true failure cause by KT-PA, after extracting candidate failure causes by TRIZ-FA

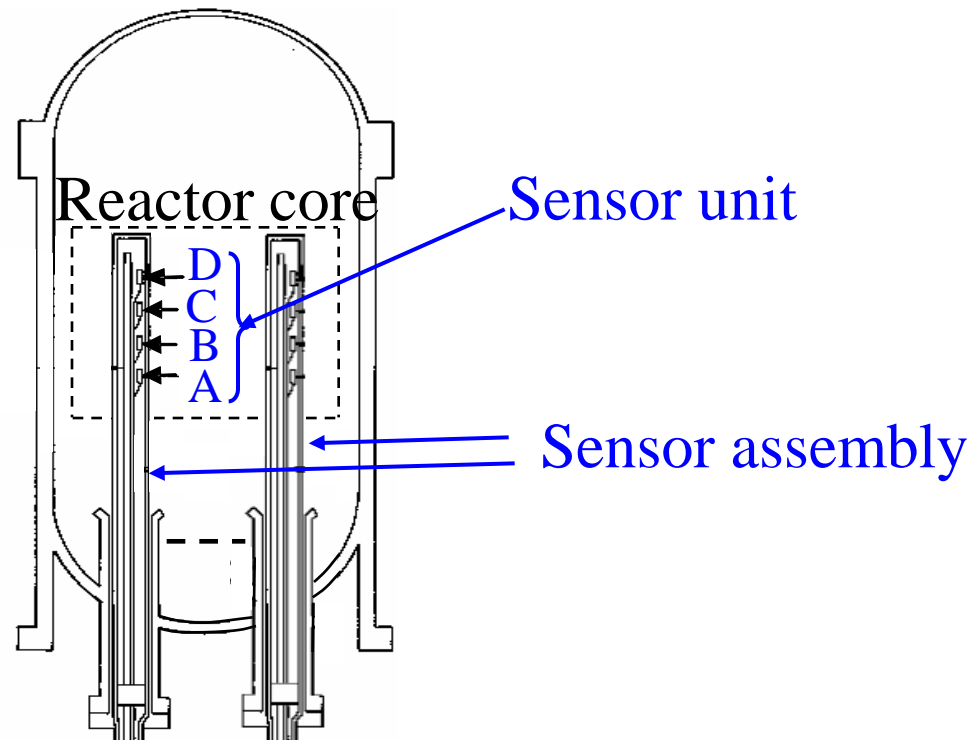


# Cause Extraction Approach



# Case Study (Cause Extraction Approach)

## Application to Nuclear Power Plant Sensor System



Event: Sensor units A, B and D in same assembly intermittently output low values.

# Cause Evaluation by KT-PA

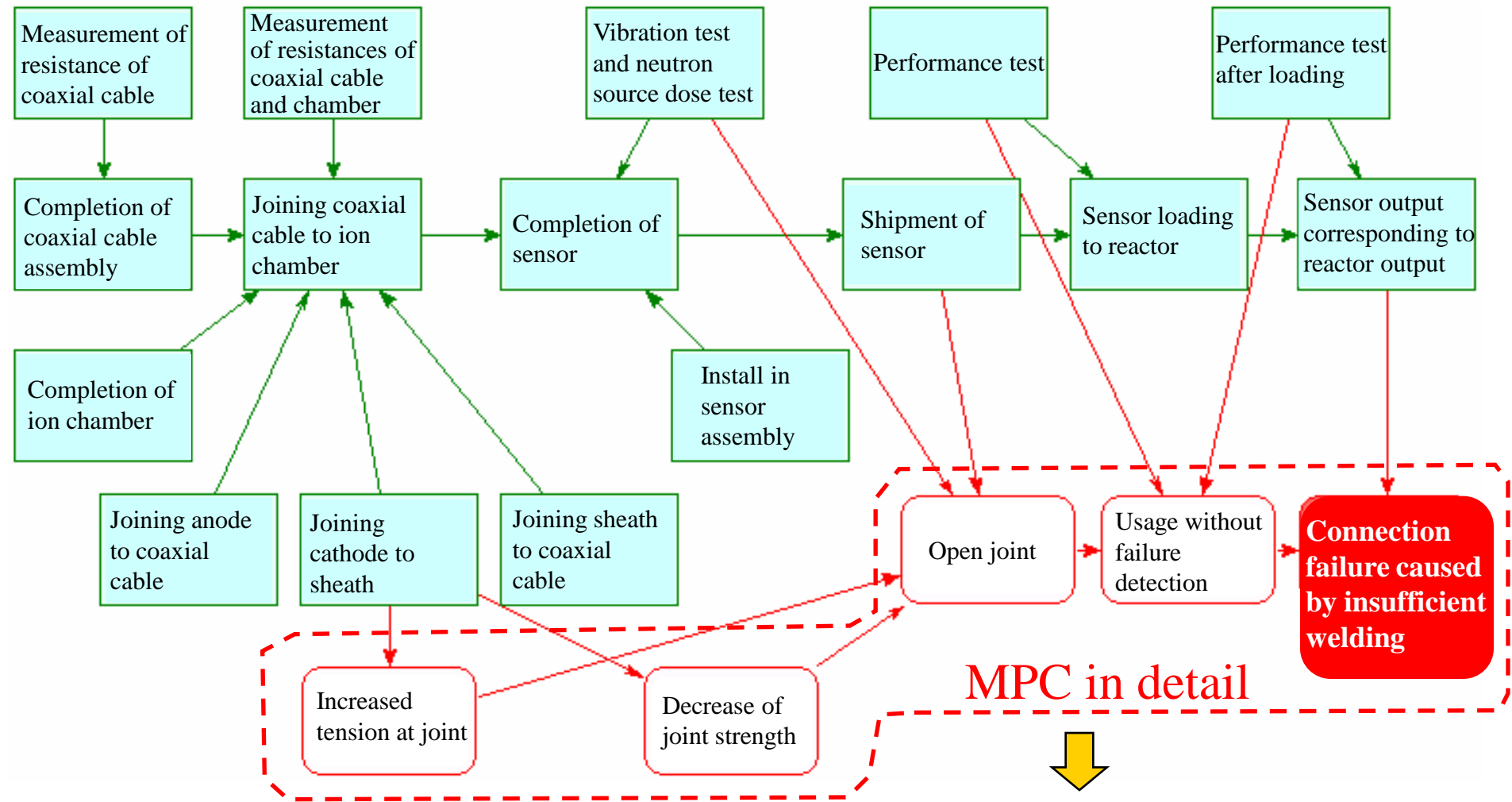
| Specific Problem Statement               |  |                  |   | Establishment of probable causes      | Evaluation of probable causes          |
|--|--|------------------|---|---------------------------------------|--|
| Output of the exchanged sensor declined. |  |                  |   |                                       | "IS/IS NOT" tests                      |
| Four aspects                             | IS   |                  | IS NOT  |                                       |  |
| WHAT                                     | Exchanged specific sensors<br>Output decrease  | ①<br>②           | Exchanged other sensors<br>Output increase  | 1) Moisture invasion to connector     | ①②③④⑤⑥⑦⑧⑨⑩<br>○△○○○△○△×                |
| WHERE                                    | Specific sensor units A, B, D channels   | ③<br>④           | Other sensor units C channel  | 2) Joint error of connector or sensor | ①②③④⑤⑥⑦⑧⑨⑩<br>○○○○○△△△○○<br><b>MPC</b> |
| WHEN                                     | After start-up<br>Plant output more than b%<br>Burst<br>A, B channels are stable in a few days | ⑤<br>⑥<br>⑦<br>⑧ | Previous cycle<br>Plant output less than b%<br>Random<br>Continuously intermittent output | 3) Leakage of gas                     | ①②③④⑤⑥⑦⑧⑨⑩<br>○○○○○△△△△×               |
| EXTENT                                   | Sensor output less than a%<br>Intermittent output at plateau                                   | ⑨<br>⑩           | Sensor output more than a%<br>Constant output at plateau                                  | 4) Induced electric noise             | ①②③④⑤⑥⑦⑧⑨⑩<br>△△△○×                    |
|  |  |                  |   | 5) Amplifier anomaly                  | ①②③④⑤⑥⑦⑧⑨⑩<br>△△△△△△△×                 |

Copyright© 2003 Kepner-Tregoe, Inc. All Rights Reserved.

MPC: Most Probable Cause

**MPC is analyzed by TRIZ-FA.**

# Visualization of Failure by TRIZ-FA



Evaluation of countermeasure and reflection on product



# Summary

- **Total number of TRIZ applications between 1997 and September 2010 was about 3950 in the Hitachi Group.**
- **TRIZ applications in actual work are promoted from top-down and bottom-up.**
- **Merging of TRIZ with other methods is developed.**
- **TRIZ effectiveness is recognized in the Hitachi Group.**
- **TRIZ activities in the Hitachi Group are being continuously promoted.**